

GigaDevice Semiconductor Inc.

Arm[®] Cortex[®]- M3/M4/M23/M33 32-bit MCU

应用笔记

AN043

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1. 介绍

Flash作为一种非易失性存储器，在微控制器系统中起着不可或缺的作用，其性能的好坏将影响整个系统的运行效率。其性能主要反映在对flash的操作时间上，包括全片擦除、页擦除、字编程时间。

该应用笔记提供了两种对flash操作时间测量的方法。

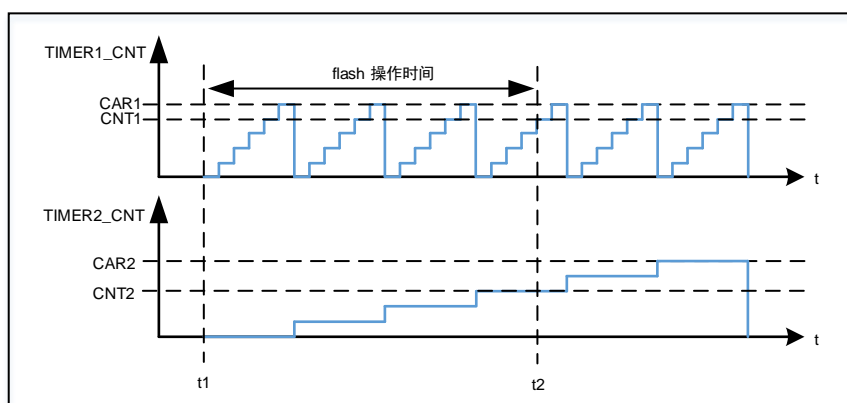
2. Flash 操作时间测量方法

2.1. 定时器计数法

定时器计数法采用 MCU 内部定时器计数，并利用计数值计算对 flash 的操作时间。该方法通过在进行 flash 操作之前清除定时器计数值并启动计数，在 flash 操作完成之后读取计数器值并关闭计数。为了提高测量精度，我们将系统运行在最高主频 64MHz，并将定时器时钟分频成 8MHz，即定时器计数周期为 0.125us。由于 L23x 定时器为 16 位定时器，则单个定时器最大只能测量 $65536 \times 0.125\mu\text{s} = 8.192\text{ms}$ ，为了提高测量时间范围，可采用定时器级联的方法。将其中一个定时器更新事件脉冲作为另一个定时器的时钟源，这样可以在保证最大精度的同时，将测量时间扩大为 $65536 \times 8.192\text{ms} = 536.870912\text{s}$ 。如 [图 2-1. 定时器测量 flash 操作时间的方法](#) 所示，flash 操作时间 t_f ：

$$t_f = t_2 - t_1 = (\text{CNT1} + (\text{CAR1} * \text{CNT2})) * 0.125\mu\text{s} \quad (2-1)$$

图 2-1. 定时器测量 flash 操作时间的方法

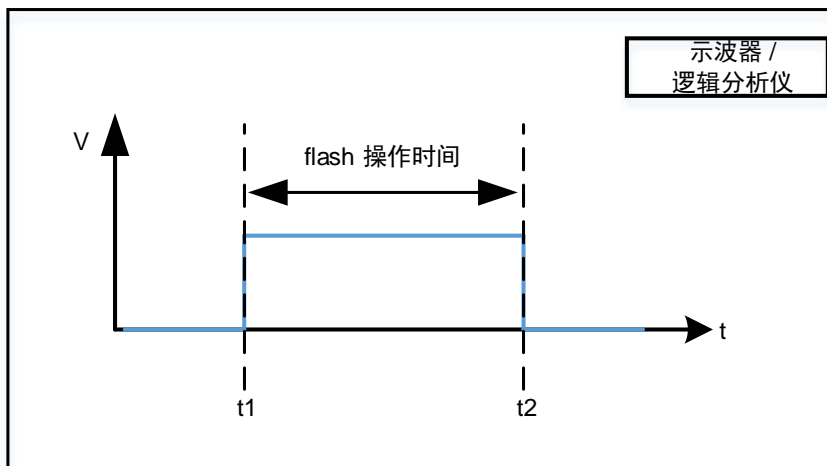


2.2. I/O 电平翻转法

采用 MCU 外部引脚输出高低电平，并使用示波器/逻辑分析仪测量该脉冲时间。

该方法通过在进行 flash 操作之前，将普通 IO 口设置为高电平；在 flash 操作完成之后，将普通 IO 口设置为低电平。通过示波器/逻辑分析仪测量测量正脉冲时间。如 [图 2-2. IO 口测量 flash 操作时间的方法](#) 所示，flash 操作时间为 $t_f = t_2 - t_1$ 。

图 2-2. IO 口测量 flash 操作时间的方法

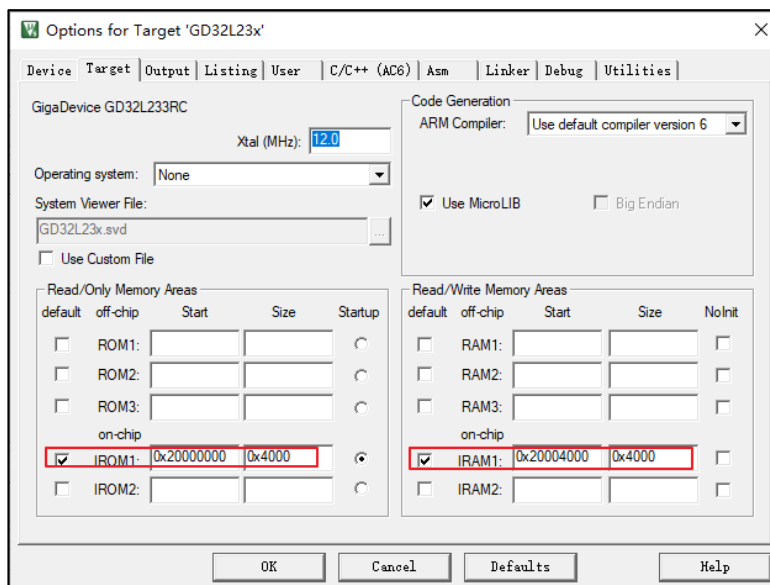


3. Flash 操作时间测量具体实现

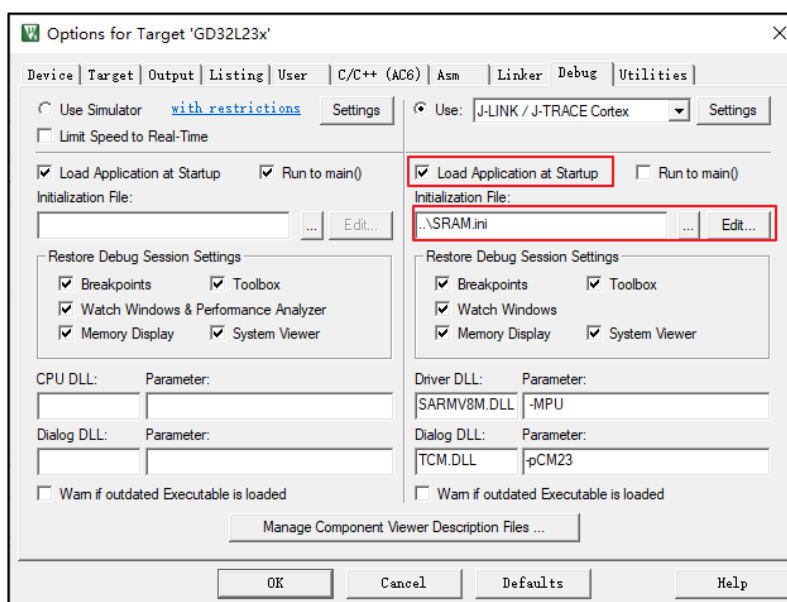
3.1. SRAM 中启动配置

为测量 flash 特性，需要把测量程序放在 sram 中运行。在 sram 中启动调试配置步骤如下：

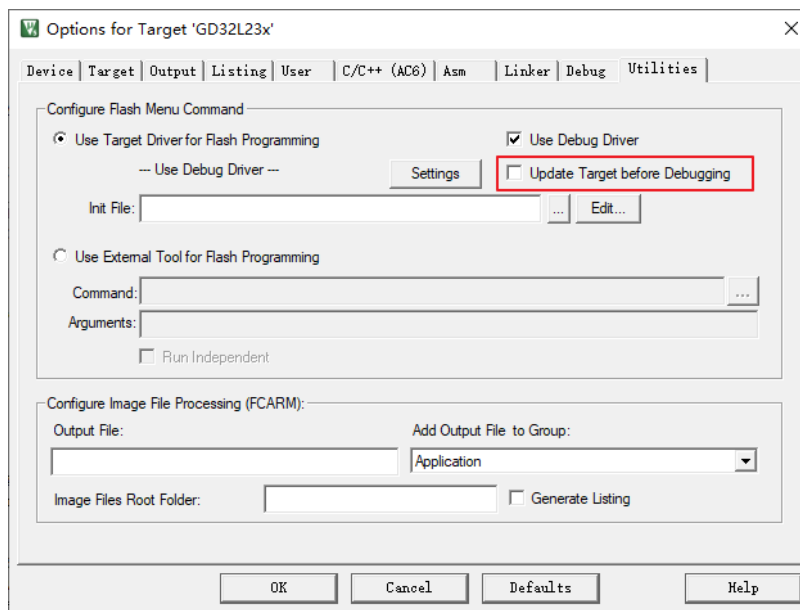
1. 根据实际 sram 空间，配置分散加载区域



2. 添加从 SRAM 中启动的初始化文件



3. 配置 Utilities 选项



4. SRAM.ini 初始化文件

```

FUNC void Setup (void) {
    /* Setup Stack Pointer */
    SP = _RDWORD(0x20000000);
    /* Setup Program Counter */
    PC = _RDWORD(0x20000004);
    /* Setup Vector Table Offset Register */
    _WDWORD(0xE000ED08, 0x20000000);
}
/* Download, Project.axf, the same with your project name */
LOAD Project.axf INCREMENTAL
/* Setup for Running */

```

3.2. 软件实现

通过宏的方式，可以使用定时器方法和 I/O 电平翻转方法分别对 flash 的全片擦除、页擦除、字编程时间进行测量。具体代码实现如下：

1. TIMER 配置

```

void timer_config(void)
{
    timer_parameter_struct timer_initpara;

    rcu_periph_clock_enable(RCU_TIMER);
    rcu_periph_clock_enable(RCU_TIMER2);

    timer_deinit(TIMER_USE);
    /* TIMER1 configuration */

```

```

timer_initpara.prescaler      = TIMER_PRESCALER;
timer_initpara.alignedmode    = TIMER_COUNTER_EDGE;
timer_initpara.counterdirection = TIMER_COUNTER_UP;
timer_initpara.period         = 65535;
timer_initpara.clockdivision  = TIMER_CKDIV_DIV1;
timer_init(TIMER_USE, &timer_initpara);

/* auto-reload preload enable */
timer_auto_reload_shadow_enable(TIMER_USE);
/* configure TIMER1 master slave mode */
timer_master_slave_mode_config(TIMER_USE, TIMER_MASTER_SLAVE_MODE_ENABLE);
timer_master_output_trigger_source_select(TIMER_USE, TIMER_TRI_OUT_SRC_UPDATE);

timer_deinit(TIMER2);
/* TIMER2 configuration */
timer_initpara.prescaler      = 0;
timer_initpara.alignedmode    = TIMER_COUNTER_EDGE;
timer_initpara.counterdirection = TIMER_COUNTER_UP;
timer_initpara.period         = 65535;
timer_initpara.clockdivision  = TIMER_CKDIV_DIV1;
timer_init(TIMER2, &timer_initpara);

timer_auto_reload_shadow_enable(TIMER2);
/* slave mode selection: TIMER2 */
timer_slave_mode_select(TIMER2, TIMER_SLAVE_MODE_EXTERNAL0);
timer_input_trigger_source_select(TIMER2, TIMER_SMCFG_TRGSEL_ITI0);
}

```

2. 主程序代码

```

/* macro definition */
#define GD32L233RC
#define TEST_MASS_ERASE          1
#define TESE_PAGE_ERASE         1
#define TEST_WORD_PROGRAMME     1
#define TIMER_CNT_MEASURE_METHOD 1

#define TIMER_PRESCALER          (8 - 1)
#define TIMER_USE                 TIMER1
#define RCU_TIMER                 RCU_TIMER1
#define PROGRAMME_DATA           0xaa55aa55
#define ADDRESS_TO_PROGRAMME     0x08000000
#define PAGE_TO_ERASE1           0x08000000

#define MEASURE_NUMS             1

```

```

#define AVERAGE_VALUE_POSITION (MEASURE_NUMS)

#if defined(GD32L233RC)
#define PAGE_SIZE1_WORD          ((4*1024)/4)
#define FLASH_SIZE_WORD          ((256*1024) /4)
#endif

#define USART_COM      USART1
/* flash operation time struct definition */
typedef struct {
    uint32_t word_programme[MEASURE_NUMS+1];
    uint32_t page_erase[MEASURE_NUMS+1];
    uint32_t mass_erase[MEASURE_NUMS+1];
}flash_operation_time_struct;

flash_operation_time_struct  flash_operation_time;

int main(void)
{
    uint16_t measure_counts = 0;
    /* gpio, timer, usart configuration */
    rcu_periph_clock_enable(RCU_GPIOC);
    gpio_mode_set(GPIOC, GPIO_MODE_OUTPUT, GPIO_PUPD_NONE,GPIO_PIN_0);
    gpio_output_options_set(GPIOC, GPIO_OTYPE_PP, GPIO_OSPEED_50MHZ, GPIO_PIN_0);
    gpio_bit_reset(GPIOC, GPIO_PIN_0);
    gd_eval_com_init(USART_COM);
    timer_config();

    fmc_unlock();
    /* mass erase measure */
#if TEST_MASS_ERASE
    do{
        {
            uint32_t i =0;
            /* mass erase, then programme full flash with PROGRAMME_DATA */
            fmc_mass_erase();
            for(i = 0; i < FLASH_SIZE_WORD; i++){
                fmc_word_program((ADDRESS_TO_PROGRAME      +      (i      *      4)),
PROGRAMME_DATA);
            }
        }
    }

#if TIMER_CNT_MESURE_METHOD
    /* clear timer count and enable timer */
    timer_disable(TIMER_USE);

```

```

timer_disable(TIMER2);
TIMER_CNT(TIMER_USE) = 0;
TIMER_CNT(TIMER2) = 0;
timer_enable(TIMER_USE);
timer_enable(TIMER2);
#else
    /* set gpio pin to high level */
    gpio_bit_set(GPIOC, GPIO_PIN_0);
#endif
    /* start mass erase */
    fmc_mass_erase();
#if TIMER_CNT_MEASURE_METHOD
    /* get the mass erase time */
    flash_operation_time.mass_erase[measure_counts] = TIMER_CNT(TIMER_USE) +
65536*TIMER_CNT(TIMER2);
#else
    /* set gpio pin to low level */
    gpio_bit_reset(GPIOC, GPIO_PIN_0);
#endif
    }while(++measure_counts < MEASURE_NUMS);
#if TIMER_CNT_MEASURE_METHOD
    /* get the average mass erase time */
    {
        uint32_t temp =0;
        for(measure_counts =0; measure_counts < MEASURE_NUMS; measure_counts++)
        {
            temp += flash_operation_time.mass_erase[measure_counts];
        }
        flash_operation_time.mass_erase[AVERAGE_VALUE_POSITION] = temp /
MEASURE_NUMS;
    }
#endif
#endif
    /* page erase measure */
#if TESE_PAGE_ERASE
measure_counts = 0;
do{
    {
        uint32_t i =0;
        /* page erase, then programme this page with PROGRAMME_DATA */
        fmc_page_erase(PAGE_TO_ERASE1);
        for(i = 0; i < 512; i++){
            fmc_word_program((ADDRESS_TO_PROGRAME + (i * 4)),

```

```

PROGRAMME_DATA);
    }
}
#endif
/* clear timer count and enable timer */
timer_disable(TIMER_USE);
timer_disable(TIMER2);
TIMER_CNT(TIMER_USE) = 0;
TIMER_CNT(TIMER2) = 0;
timer_enable(TIMER_USE);
timer_enable(TIMER2);
#else
/* set gpio pin to high level */
gpio_bit_set(GPIOC, GPIO_PIN_0);
#endif
/* start page erase */
fmc_page_erase(PAGE_TO_ERASE1);
#endif
/* get the page erase time */
flash_operation_time.page_erase[measure_counts] = TIMER_CNT(TIMER_USE) +
65536*TIMER_CNT(TIMER2);
#else
/* set gpio pin to low level */
gpio_bit_reset(GPIOC, GPIO_PIN_0);
#endif
}while(++measure_counts < MEASURE_NUMS);
#endif
/* get the average page erase time */
{
uint32_t temp =0;
for(measure_counts =0; measure_counts < MEASURE_NUMS; measure_counts++)
{
temp += flash_operation_time.page_erase[measure_counts];
}
flash_operation_time.page_erase[AVERAGE_VALUE_POSITION] = temp /
MEASURE_NUMS;
}
#endif
#endif
/* word programme measure */
#endif TEST_WORD_PROGRAMME
measure_counts = 0;
do{

```

```

        fmc_page_erase(PAGE_TO_ERASE1);
#if TIMER_CNT_MESURE_METHOD
    /* clear timer count and enable timer */
    timer_disable(TIMER_USE);
    timer_disable(TIMER2);
    TIMER_CNT(TIMER_USE) = 0;
    TIMER_CNT(TIMER2) = 0;
    timer_enable(TIMER_USE);
    timer_enable(TIMER2);
#else
    /* set gpio pin to high level */
    gpio_bit_set(GPIOC, GPIO_PIN_0);
#endif

    /* start word programme */
    fmc_word_program(ADDRESS_TO_PROGRAMME      +(4*measure_counts)
PROGRAMME_DATA);
#if TIMER_CNT_MESURE_METHOD
    /* get the word programme time */
    flash_operation_time.word_programme[measure_counts] = TIMER_CNT(TIMER_USE)+
65536*TIMER_CNT(TIMER2);
#else
    /* set gpio pin to low level */
    gpio_bit_reset(GPIOC, GPIO_PIN_0);
#endif

    }while(++measure_counts < MEASURE_NUMS);
#if TIMER_CNT_MESURE_METHOD
    /* get the average word programme time */
    {
        uint32_t temp =0;
        for(measure_counts =0; measure_counts < MEASURE_NUMS; measure_counts++)
        {
            temp += flash_operation_time.word_programme[measure_counts];
        }
        flash_operation_time.word_programme[AVERAGE_VALUE_POSITION] = temp /
MEASURE_NUMS;
    }
#endif
#endif

#if TIMER_CNT_MESURE_METHOD
    /* print flash operation time by usart */
    printf("word programme time:%.2f(us)\r\npage erase time:%.2f (us)\r\nmass erase time:%.2f
(us)\r\n",

```

```
flash_operation_time.word_programme[AVERAGE_VALUE_POSITION]*0.125, \  
flash_operation_time.page_erase[AVERAGE_VALUE_POSITION]*0.125, \  
flash_operation_time.mass_erase[AVERAGE_VALUE_POSITION]*0.125);  
#endif  
/* infinite loop */  
while(1){  
  
}  
}
```

4. 测试结果

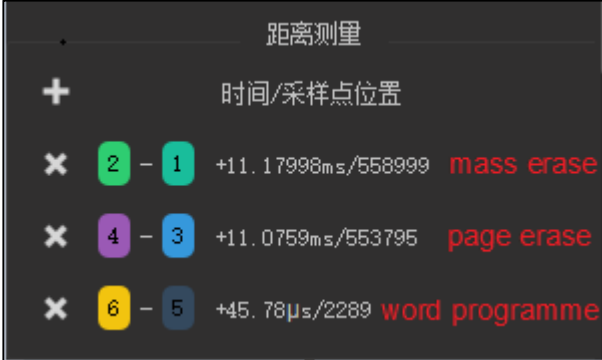
打开宏 TEST_MASS_ERASE、TESE_PAGE_ERASE、TEST_WORD_PROGRAMME、TIMER_CNT_MESURE_METHOD。编译工程，点击调试按钮，点击全速运行。[图 4-1. 串口输出 flash 操作时间](#)结果如下。

图 4-1. 串口输出 flash 操作时间

```
word programe time:46.00(us)
page erase time:11072.63(us)
mass erase time:11176.75(us)
```

打开宏 TEST_MASS_ERASE、TESE_PAGE_ERASE、TEST_WORD_PROGRAMME，关闭宏 TIMER_CNT_MESURE_METHOD。编译工程，点击调试按钮，点击全速运行。[图 4-2. 逻辑分析仪输出 flash 操作时间](#)结果如下。

图 4-2. 逻辑分析仪输出 flash 操作时间



距离测量

	+	时间/采样点位置	
×	2	- 1	+11.17998ms/558999 mass erase
×	4	- 3	+11.0759ms/553795 page erase
×	6	- 5	+45.78μs/2289 word programme

5. 版本历史

表 5-1. 版本历史

版本号.	说明	日期
1.0	首次发布	2021 年 11 月 8 日

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